

MOSFET

8A, 500V, 0.85Ω, N-CHANNEL POWER MOSFET

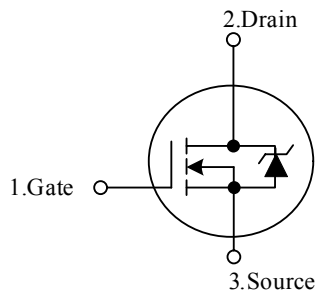
■ DESCRIPTION

The N-Channel enhancement mode silicon gate power MOSFET is designed for high voltage, high speed power switching applications such as switching regulators, switching converters, solenoid, motor drivers, relay drivers.

■ FEATURES

- * 8A, 500V, Low $R_{DS(ON)}$ (0.85Ω)
- * Single Pulse Avalanche Energy Rated
- * Rugged - SOA is Power Dissipation Limited
- * Fast Switching Speeds
- * Linear Transfer Characteristics
- * High Input Impedance

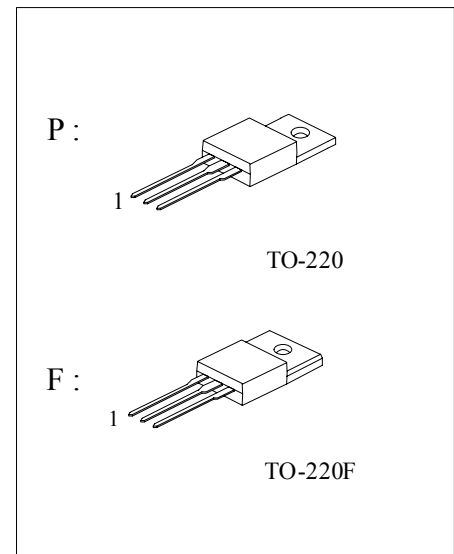
■ SYMBOL



■ ORDERING INFORMATION

| Order Number | Package | Pin Assignment | | | Packing |
|--------------|---------|----------------|---|---|---------|
| | | 1 | 2 | 3 | |
| FTK840P | TO-220 | G | D | S | Tube |
| FTK840F | TO-220F | G | D | S | Tube |

Note: Pin Assignment: G: Gate D: Drain S: Source



■ ABSOLUTE MAXIMUM RATINGS (T_C = 25°C, unless otherwise specified)

| PARAMET | | SYMBOL | RATINGS | UNIT |
|-------------------------------------------------------------------------------------------------------------------------------------------------------|------------------------|------------------|------------|------|
| Drain to Source Voltage (T _J = 25°C ~ 125°C) | | V _{DS} | 500 | V |
| Drain to Gate Voltage (R _{GS} = 20kΩ) (T _J = 25°C ~ 125°C) | | V _{DGR} | 500 | V |
| Gate to Source Voltage | | I _{GS} | ±20 | V |
| Drain Current | Continuous | I _D | 8.0 | A |
| | T _C = 100°C | I _D | 5.1 | A |
| | Pulsed | I _{DM} | 32 | A |
| Maximum Power Dissipation Derating above 25°C | | P _D | 125 | W |
| | | | 1.0 | W/°C |
| Single Pulse Avalanche Energy Rating (V _{DD} =50V, starting T _J =25°C, L=14mH, R _G =25Ω, peak I _{AS} = 8A) | | E _{AS} | 510 | mJ |
| Operating Temperature Range | | T _{OPR} | -55 ~ +150 | °C |
| Storage Temperature Range | | T _{STG} | -55 ~ +150 | °C |

Note: 1. Signified recommend operating range that indicates conditions for which the device is intended to be functional, but does not guarantee specific performance limits.

2. Absolute maximum ratings indicate limits beyond which damage to the device may occur.

■ THERMAL DATA

| PARAMETER | SYMBOL | RATINGS | UNIT |
|-------------------------------------|-----------------|---------|--------|
| Thermal Resistance Junction-Ambient | θ _{JA} | 62.5 | °C / W |
| Thermal Resistance Junction-Case | θ _{Jc} | 1.0 | |

■ ELECTRICAL CHARACTERISTICS (T_C = 25°C, unless Otherwise specified.)

| PARAMETER | SYMBOL | TEST CONDITIONS | MIN | TYP | MAX | UNIT |
|----------------------------------------|-----------------------|----------------------------------------------------------------------------------------------------------------------------------------------------|-----|------|------|------|
| Drain-Source Breakdown Voltage | BV _{DSS} | I _D = 250μA, V _{GS} = 0V (Figure 16) | 500 | | | V |
| Gate to Threshold Voltage | V _{GS(THR)} | V _{DS} = V _{GS} , I _D = 250μA | 2.0 | | 4.0 | V |
| On-State Drain Current (Note 1) | I _{D(ON)} | V _{DS} > I _{D(ON)} × R _{DS(ON)MAX} , V _{GS} = 10V | 8.0 | | | A |
| Zero Gate Voltage Drain Current | I _{DSS} | V _{DS} = Rated BV _{DSS} , V _{GS} = 0V | | | 25 | μA |
| | | V _{DS} = 0.8 × Rated BV _{DSS} , V _{GS} = 0V, T _J = 125°C | | | 250 | μA |
| Gate to Source Leakage Current | I _{GSS} | V _{DS} = ±20V | | | ±100 | nA |
| Drain to Source On Resistance (Note 1) | R _{DS(ON)} | I _D = 4.4A, V _{GS} = 10V (Figure 14, 15) | | 0.8 | 0.85 | Ω |
| Forward Transconductance (Note 1) | g _{FS} | V _{DS} ≥ 50V, I _D = 4.4A (Figure 18) | 4.9 | 7.4 | | S |
| Turn-On Delay Time | t _{DLY(ON)} | V _{DD} = 250V, I _D ≈ 8.0A, R _G = 9.1Ω, R _L = 30Ω (Note 2) | | 15 | | ns |
| Rise Time | t _r | | | 21 | | ns |
| Turn-Off Delay Time | t _{DLY(OFF)} | | | 50 | | ns |
| Fall Time | t _f | | | 20 | | ns |
| Total Gate Charge | Q _{G(TOT)} | V _{GS} = 10V, I _D = 8A, V _{DS} = 0.8 × Rated BV _{DSS} I _{G(REF)} = 1.5mA (Figure 20) (Note 3) | | 42 | | nC |
| Gate to Source Charge | Q _{GS} | | | 7 | | nC |
| Gate to Drain "Miller" Charge | Q _{GD} | | | 22 | | nC |
| Input Capacitance | C _{ISS} | V _{DS} = 25V, V _{GS} = 0V, f = 1MHz (Figure 17) | | 1225 | | pF |
| Output Capacitance | C _{OSS} | | | 20 | | pF |
| Reverse - Transfer Capacitance | C _{RSS} | | | 85 | | pF |

Note: 1. Pulse Test: Pulse width ≤ 300μs, Duty Cycle ≤ 2%.

2. MOSFET Switching Times are Essentially Independent of Operating Temperature.

3. Gate Charge is Essentially Independent of Operating Temperature.



■ ELECTRICAL CHARACTERISTICS(Cont.)

| PARAMETER | SYMBOL | TEST CONDITIONS | MIN | TYP | MAX | UNIT |
|---------------------------------------------|-----------|--------------------------------------------------------------------------------------|-----|-----|-----|---------------|
| SOURCE TO DRAIN DIODE SPECIFICATIONS | | | | | | |
| Source to Drain Diode Voltage (Note 1) | V_{SD} | $T_J = 25^{\circ}\text{C}$, $I_{SD} = 8\text{A}$, $V_{GS} = 0\text{V}$ (Figure 19) | | | 2 | V |
| Continuous Source to Drain Current | I_S | Note 2 | | | 8 | A |
| Pulse Source to Drain Current | I_{SDM} | Note 2 | | | 32 | A |
| Reverse Recovery Time | t_{RR} | $T_J = 25^{\circ}\text{C}$, $I_{SD} = 8\text{A}$, | | 475 | | ns |
| Reverse Recovery Charge | Q_{RR} | $di_{SD}/dt = 100\text{ A}/\mu\text{s}$ | | 4.6 | | μC |

Note:

1. Pulse Test: Pulse width $\leq 300\mu\text{s}$, Duty cycle $\leq 2\%$
2. Modified MOSFET symbol showing the integral reverse P-N junction diode as below.

■ TEST CIRCUITS AND WAVEFORMS

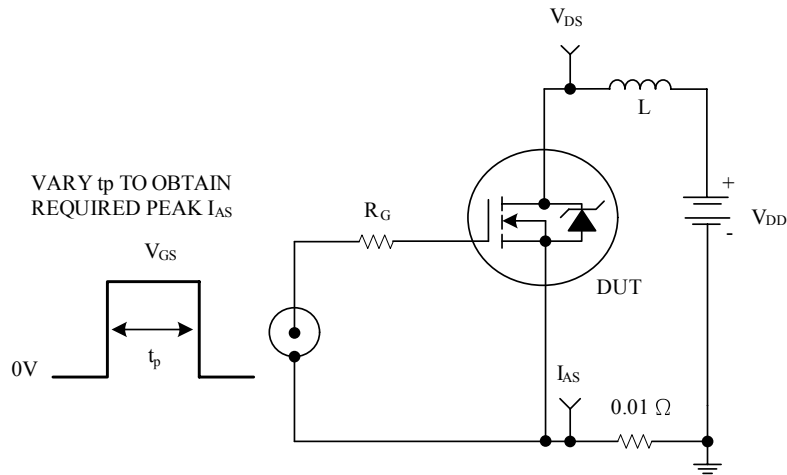


FIGURE 1. UNCLAMPED ENERGY TEST CIRCUIT

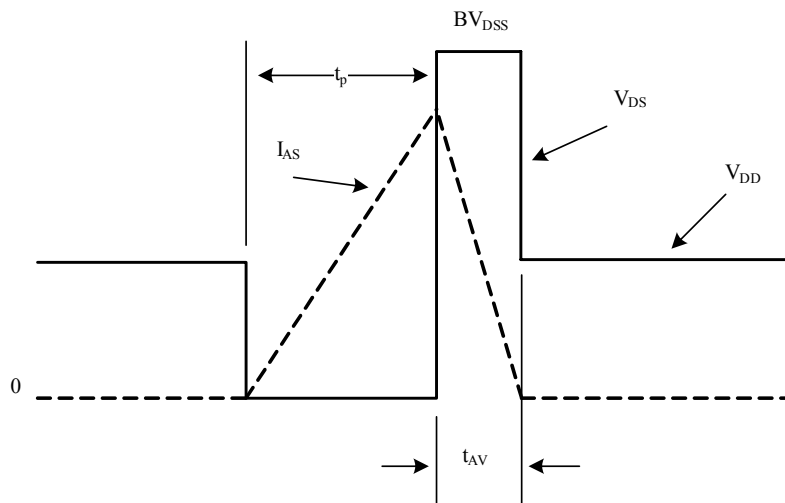


FIGURE 2. UNCLAMPED ENERGY WAVEFORMS

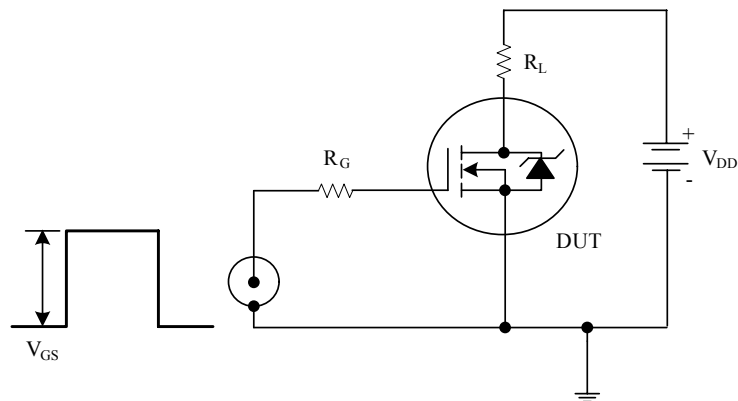


FIGURE 3. SWITCHING TIME TEST CIRCUIT

■ TEST CIRCUITS AND WAVEFORMS(cont.)

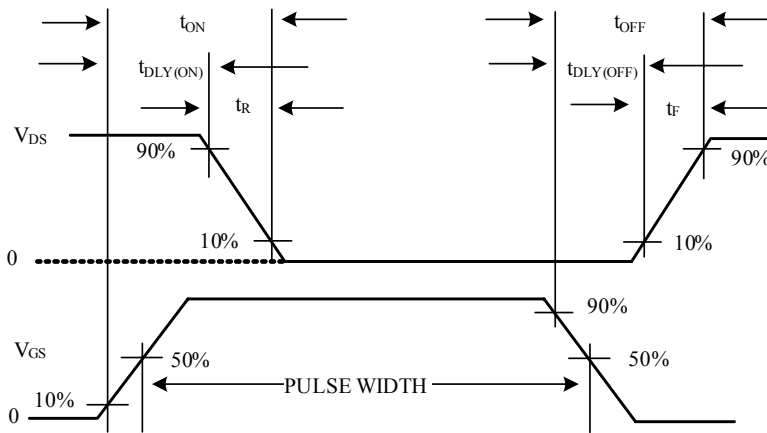


FIGURE 4. RESISTIVE SWITCHING WAVEFORMS

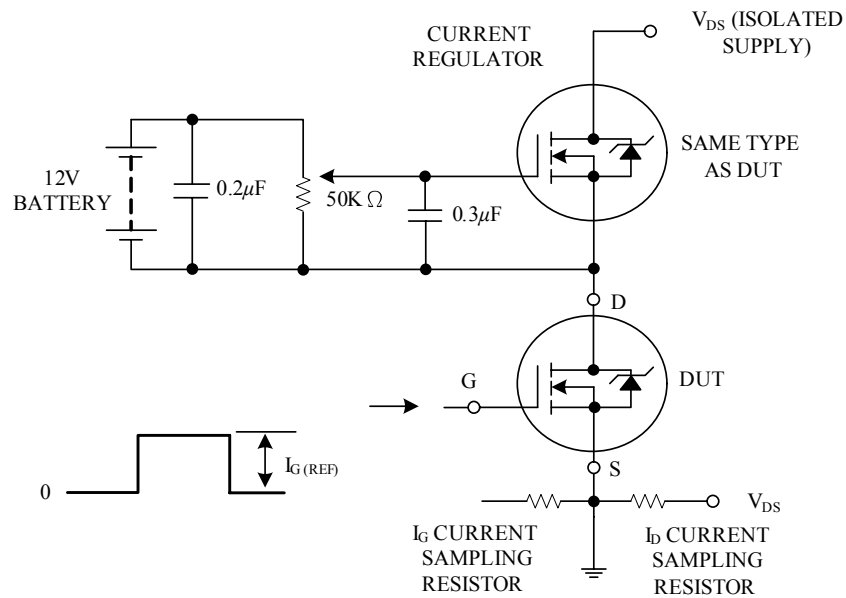


FIGURE 5. GATE CHARGE TEST CIRCUIT

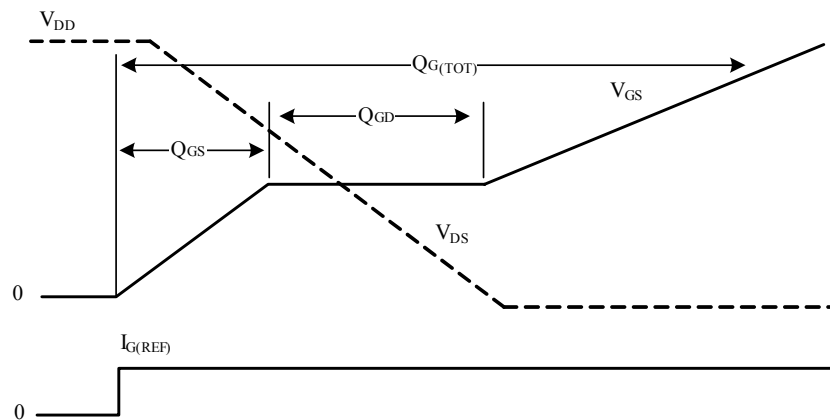


FIGURE 6. GATE CHARGE WAVEFORMS

TYPICAL CHARACTERISTICS

FIGURE 7. NORMALIZED POWER DISSIPATION vs CASE TEMPERATURE

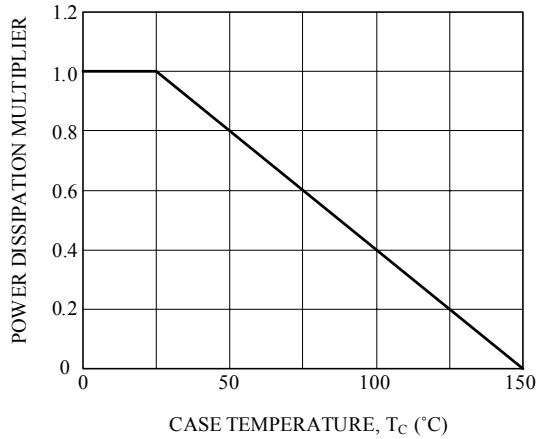


FIGURE 8. MAXIMUM CONTINUOUS DRAIN CURRENT vs CASE TEMPERATURE

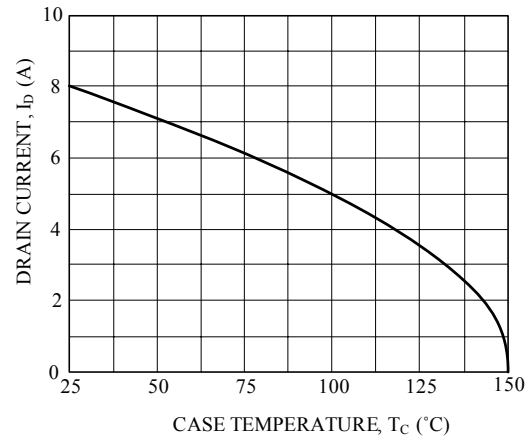


FIGURE 9. NORMALIZED MAXIMUM TRANSIENT THERMAL IMPEDANCE

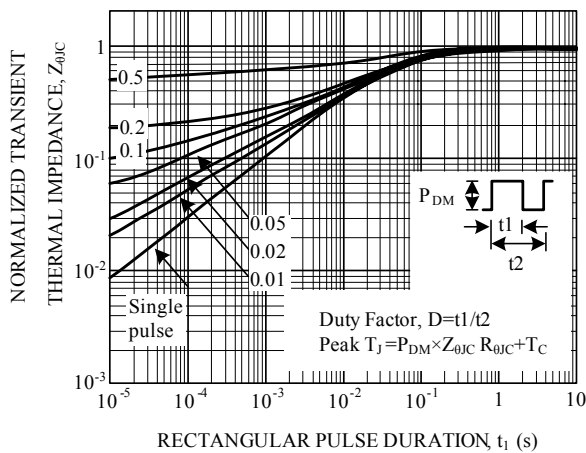


FIGURE 10. FORWARD BIAS SAFE OPERATING AREA

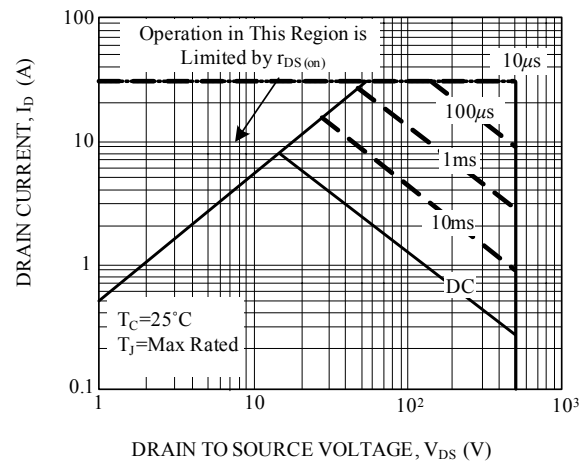


FIGURE 11. OUTPUT CHARACTERISTICS

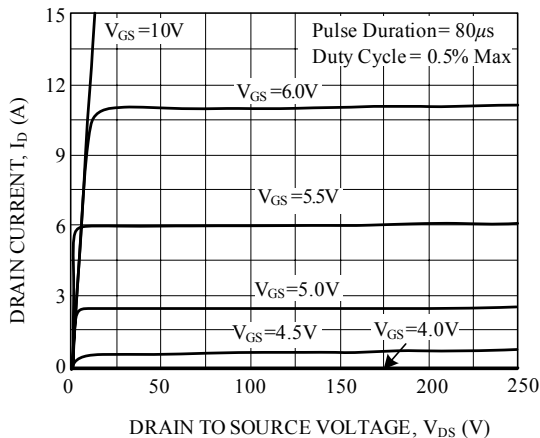
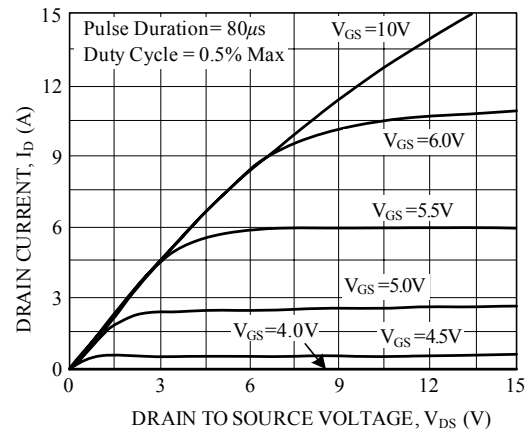


FIGURE 12. SATURATION CHARACTERISTICS



TYPICAL CHARACTERISTICS(Cont.)

Figure 13. Transfer Characteristics

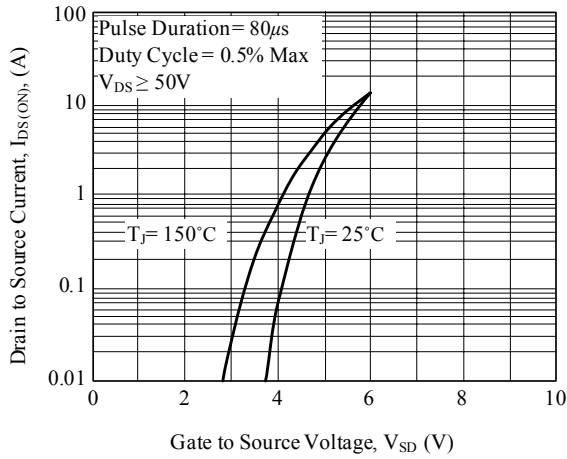


Figure 14. Drain to Source on Resistance vs. Voltage and Drain Current

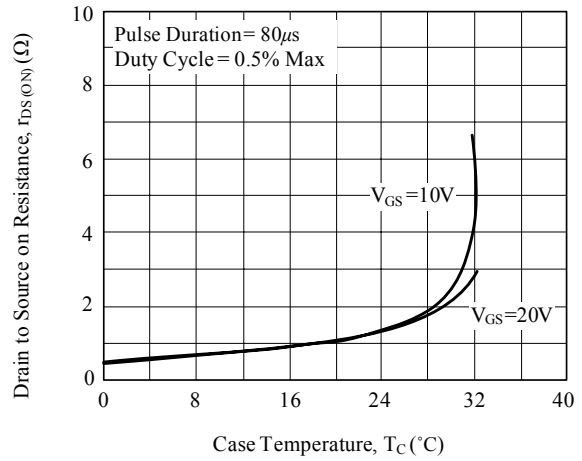


Figure 15. Normalized Drain to Source on Resistance vs. Junction Temperature

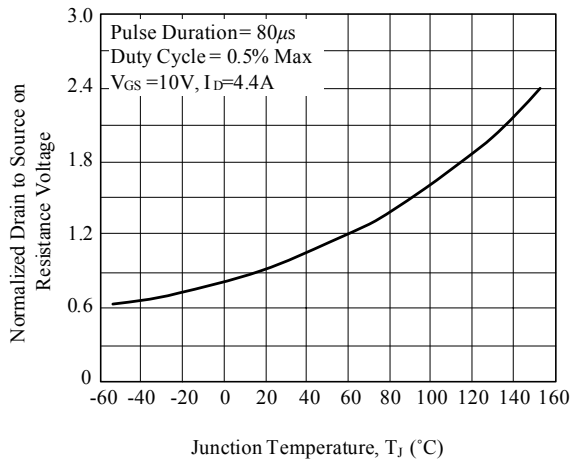


Figure 16. Normalized Drain to Source Breakdown Voltage vs. Junction Temperature

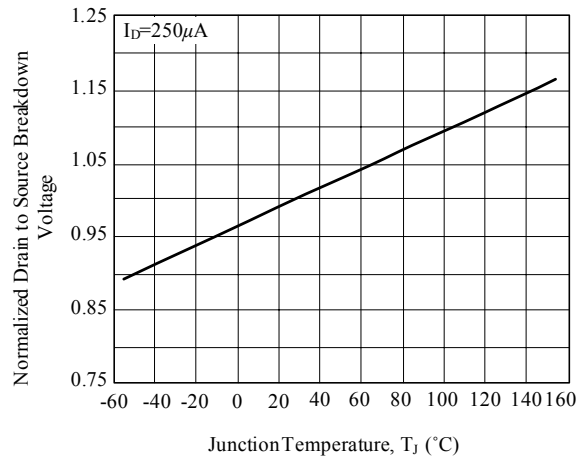


Figure 17. Capacitance vs. Drain to Source Voltage

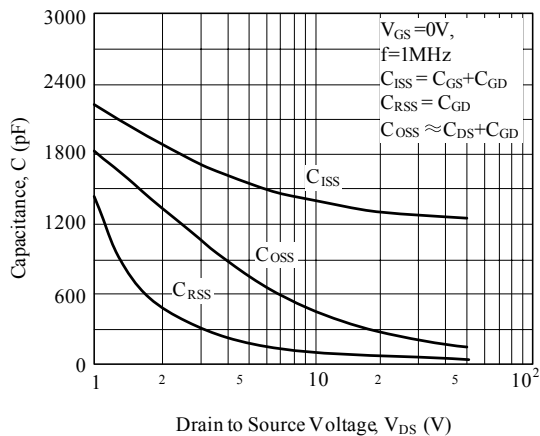
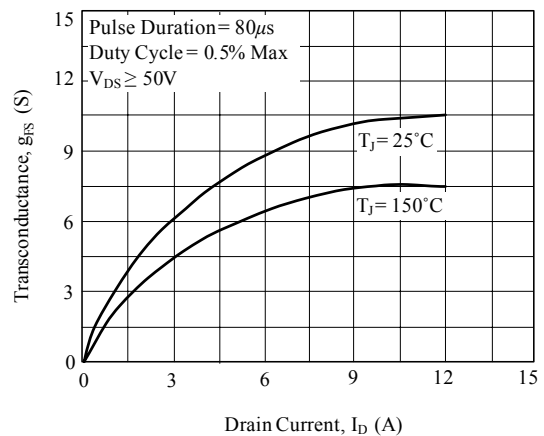


Figure 18. Transconductance vs. Drain Current



■ TYPICAL CHARACTERISTICS(Cont.)

Figure 19. Source to Drain DIODE Voltage

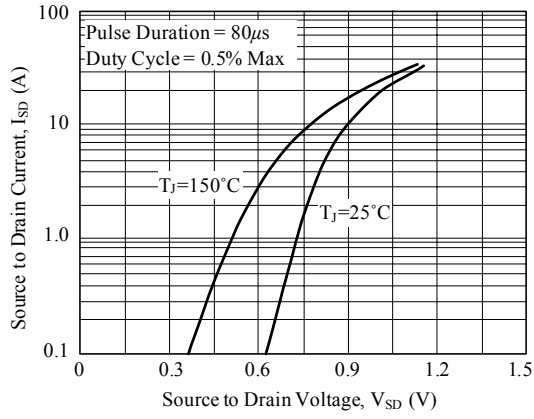


Figure 20. Gate to Source Voltage vs. Gate Charge

